

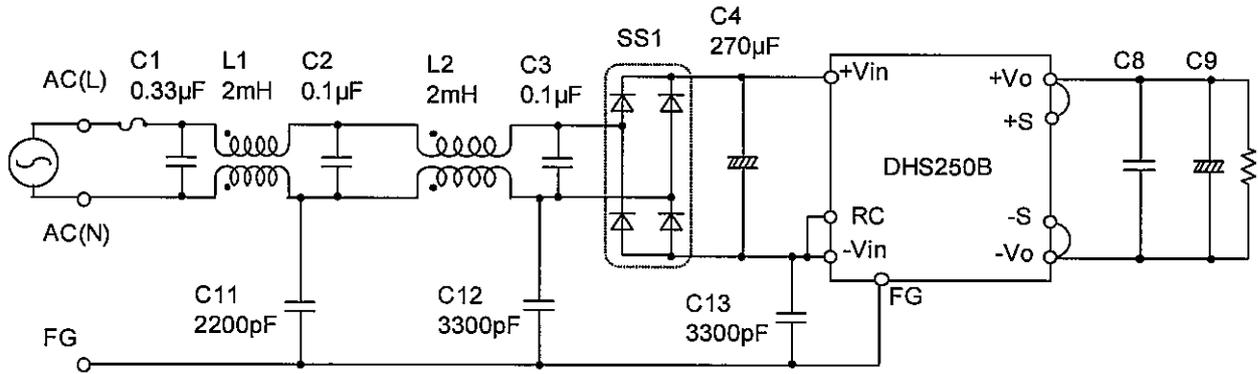


**DHS250B series EMI/EMS Test result**

Approved : *Tatsuya Mano*  
Tatsuya Mano

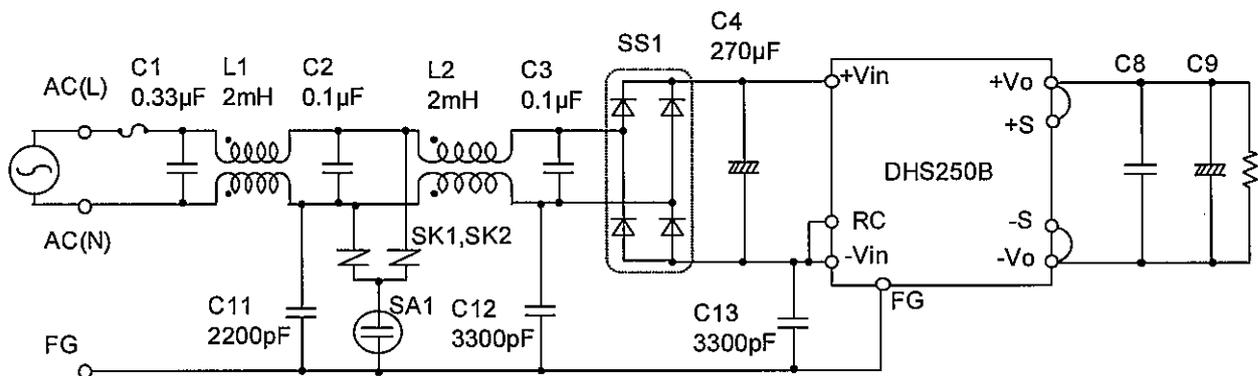
Prepared : *Daisuke Tsuchida*  
Daisuke Tsuchida

No.	Test item	Conditions	Conditions of Acceptability	Result
1	Line conduction	(1) Rated input(AC230V) (2) Rated load (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Meets the undermentioned standard. FCC Part15 classA , VCCI classA CISPR22 classA , EN55011-A	OK
2	Radiated emission	(1) Rated input(AC230V) (2) Rated load (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Meets the undermentioned standard. FCC Part15 classA , VCCI classA CISPR22 classA , EN55011-A	OK
3	Static electricity immunity test (EN61000-4-2)	(1) Rated input(AC230V) (2) Rated load (3) Ambient temp. 25±10°C (4) Contact discharge voltage 8[kV] (EN61000-4-2 Level 4) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
4	Radiated, radio-frequency, electromagnetic field immunity test (EN61000-4-3)	(1) Rated input(AC230V) (2) Rated load (3) Ambient temp. 25±10°C (4)Testing field strength 10[V/m] (EN61000-4-3 Level 3) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
5	Electrical fast transient/ burst immunity test (EN61000-4-4)	(1) Rated input(AC230V) (2) Rated load (3) Ambient temp. 25±10°C (4) Test peak voltage 4[kV] (IEC61000-4-4 Level 4) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
6	Surge immunity test (EN61000-4-5)	(1) Rated input(AC230V) (2) Rated load (3) Ambient temp. 25±10°C (4) Test voltage Line to line 2[kV] (Level 3) Line to earth 4[kV] (Level 4) (5) Testing circuitry Fig.2	(1)The power supply is not stop (2)Circuit does not malfunction. (3)No abnormality of the insulation destruction etc. (4)Parts are no damaged.	OK
7	Immunity to conducted disturbances, induced by radio-frequency fields (EN61000-4-6)	(1) Rated input (AC230V) (2) Rated load (3) Ambient temp. 25±10°C (4) Voltage level (e.m.f.) 10[V] (Level 3) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK



- L1,L2 : SC-05-200(NEC TOKIN)  
 SS1 : D10XB60(SINDENGEN)  
 C8 : DHS250B03 10 µ F      C9 : DHS250B03 2200 µ F  
      DHS250B05 10 µ F      DHS250B05 2200 µ F  
      DHS250B07 10 µ F      DHS250B07 2200 µ F  
      DHS250B12 10 µ F      DHS250B12 1000 µ F  
      DHS250B15 10 µ F      DHS250B15 1000 µ F  
      DHS250B24 4.7 µ F      DHS250B24 470 µ F  
      DHS250B28 4.7 µ F      DHS250B28 470 µ F  
      DHS250B48 2.2 µ F      DHS250B48 330 µ F

Fig.1 Testing circuitry



- L1,L2 : SC-05-200(NEC TOKIN)  
 SS1 : D10XB60(SINDENGEN)  
 SK1,SK2 : ENE471D-10A(FUJI ELECTRIC CO.,LTD)  
 SA1 : DSA-302MA(MITSUBISHI MATERIALS COAP.)  
 C8 : DHS250B03 10 µ F      C9 : DHS250B03 2200 µ F  
      DHS250B05 10 µ F      DHS250B05 2200 µ F  
      DHS250B07 10 µ F      DHS250B07 2200 µ F  
      DHS250B12 10 µ F      DHS250B12 1000 µ F  
      DHS250B15 10 µ F      DHS250B15 1000 µ F  
      DHS250B24 4.7 µ F      DHS250B24 470 µ F  
      DHS250B28 4.7 µ F      DHS250B28 470 µ F  
      DHS250B48 2.2 µ F      DHS250B48 330 µ F

Fig.2 Surge immunity Testing circuitry